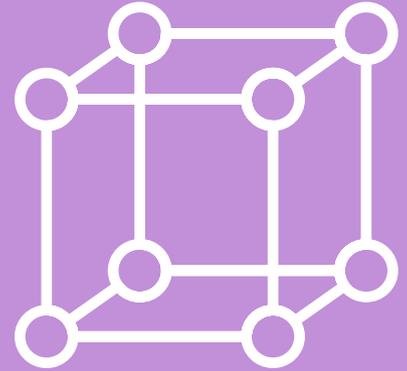


# Special materials



Pyrometers for special applications and materials

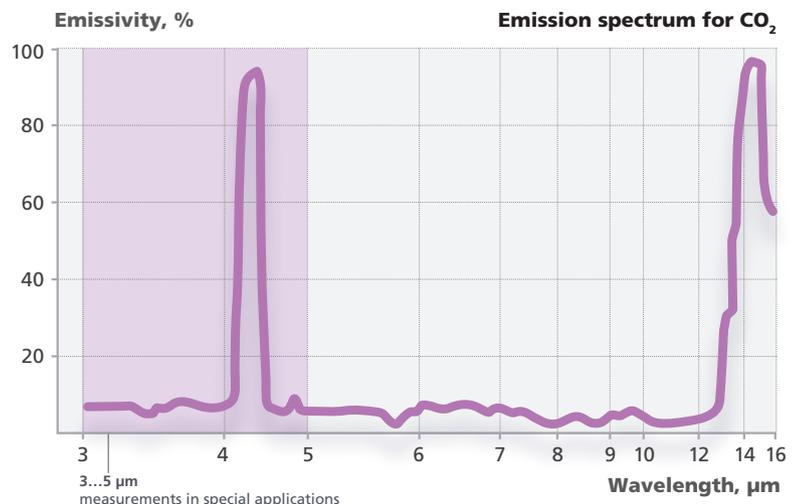
## EMISSIVITY OF SPECIAL MATERIALS

LumaSense produces a wide range of specialized pyrometers beyond those described in the previous sections. These pyrometers are customized to address specific applications and materials, and are often available with the needed accessories to provide a complete solution package.

To measure temperatures for these specialized applications, one must carefully understand the emissivity, reflectance, and transmissions of the objects to be measured. We then select the proper detectors and filters to maximize the detected signal. For example, when measuring the temperature of a combustion flame where there is expected to be significant CO<sub>2</sub> content, we select a narrow band filter at 4.5 μm where the emission from this gas is high (see figure). If we instead choose a 3.9 μm filter, then we can effectively avoid the CO<sub>2</sub> and H<sub>2</sub>O emission bands, and look through the flame.

If you have a specialized need, which is not covered with the pyrometers below, please consult our Applications Engineering Team.

**SOME EXAMPLE APPLICATIONS INCLUDE:**  
Measuring flame or gas temperature, by monitoring the CO<sub>2</sub> absorption line  
Measuring temperature on thin plastic films  
Measuring Silicon and Sapphire wafers in Semiconductor & Compound Semi processes



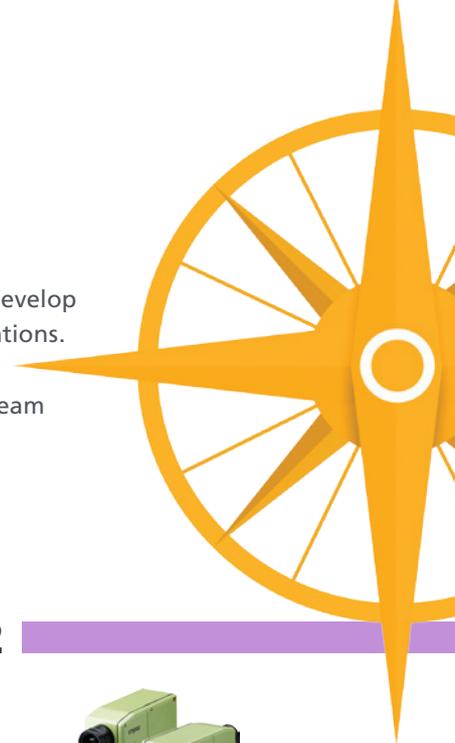
## APPLICATION CONSULTING AND SUPPORT

### Supporting Your Applications Needs

The LumaSense Global Applications Engineering team is staffed with Sr. Engineers to help develop new solutions for customers worldwide, with focus on core markets and challenging applications.

LumaSense Technologies is known for its ability to build products for custom applications using our temperature and gas sensing products to meet the stringent design requirements of the energy, industrial and clean technology markets.

Contact our dedicated Customer Care Team to request an application consultation.

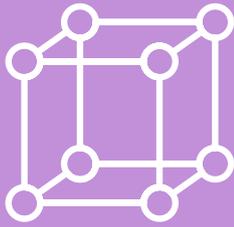


## SERIES 5, 6

## SERIES 12



Model	IN 5/9 plus	ISR 6 Advanced	IS 12-AI, 12-AI/S	IS 12-Si		
<b>Brief Description</b>	Digital pyrometer especially designed for measurement of sapphire. With analog output, digital interface, max. / min. value storage, different optics, laser targeting light.	Highly accurate digital, fast pyrometer in 2-color design (switchable to mono mode) with analog output and digital interface, focusable optics, and integrated LED display.	Special version of the IS 12, designed for the measurement of Aluminum. IS 12-AI/S with built-in scanner, scanning angle adjustable between 0...4°, scanning frequency between 0...10 Hz.	Dedicated version of the IS 12, designed for measuring silicon wafers.		
<b>Temperature Ranges</b>	0...1500 °C	600...1400 °C 700...1800 °C 800...2500 °C 1000...3000 °C	350...900 °C 400...1050 °C	350...1000 °C 400...900 °C 400...1300 °C 500...1800 °C		
<b>Spectral Range</b>	8...9.7 μm	Ch. 1: 0.9 μm Ch. 2: 1.05 μm	Aluminum absorption filter	Silicon absorption filter		
<b>Measurement Uncertainty</b>	0.6% oR or 3 °C	< 1500 °C: 0.3% oR + 2 °C > 1500 °C: 0.6% oR	0.3% oR + 1 °C	< 1500 °C: 0.3% oR + 1 °C > 1500 °C: 0.5% oR		
<b>Repeatability</b>	0.3% oR or 0.6 °C	0.15% oR + 1 °C	0.1% oR + 1 °C	0.1% oR + 1 °C		
<b>Optics</b>	6 fixed optics: a = 95 mm a = 112 mm a = 160 mm a = 280 mm a = 400 mm a = 620 mm	Manually focusable between 210...5000 mm	MB 9 5 fixed optics: a = 112 mm a = 240 mm a = 660 mm a = 1300 mm a = 5600 mm	MB 10.5 6 fixed optics: a = 80 mm a = 160 mm a = 250 mm a = 660 mm a = 1300 mm a = 5600 mm	6 fixed optics: a = 80 mm a = 120 mm a = 250 mm a = 660 mm a = 1300 mm a = 5600 mm	3 focusable optics: 275...520 mm 385...1125 mm 540...9000 mm
<b>Field of View</b> (Minimum spot size Ø in mm)	60:1 (1.7 mm)	min. 350:1 (min. 0.6 mm) Option: line optics	min. 120:1 (1.1 mm)	Fixed Optics: min. 370:1 (0.6 mm) Focusable Optics: min. 130:1 (2.3 mm)		
<b>Alignment</b>	Laser targeting	Laser targeting or through-lens-sighting or color TV camera	Laser targeting and through-lens-sighting	Laser targeting and through-lens-sighting		
<b>Exposure time t<sub>90</sub></b>	180 ms, adjustable up to 30 s	2 ms, adjustable up to 10 s	< 1.5 ms, adjustable up to 10 s	10 ms, adjustable up to 10 s		
<b>Output</b>	0/4...20 mA, RS232 (RS485 on request)	0/4...20 mA, RS485, (RS232 optional)	0/4...20 mA, RS232 or RS485 (switchable)	0/4...20 mA, RS232 or RS485 (switchable)		



## SPECIAL MATERIALS

### FEATURED PRODUCT

## IPE 140

Pyrometers available with various dedicated filters for specific applications.

Next to the standard versions, these pyrometers are also available with specific filters to measure dedicated materials, including thin PE and PP foils, CO<sub>2</sub> or the measurement through clean combustion flames and gases.



## SERIES 50



	SERIES 50		SERIES 140	
Model	IS 50-Si-LO plus	IS 50-Al-LO plus	IPE 140/34	IPE 140/45
<b>Brief Description</b>	Special version of the IS 50-LO plus with special wavelength for the measurement of silicon wafers.	Special version of the IS 50-LO plus with special wavelength for the measurement of Aluminum.	Special version of the IPE 140 for measurement of thin PE and PP foils with a minimum material thickness of only 30 µm.	Special version of the IPE 140 for measurement of combustion flames and hot gases containing CO <sub>2</sub> . This pyrometer is used e.g. in the LumaSense FEGT system for continuous measurement of the Furnace Exit-Gas Temperature in boilers and furnaces.
<b>Temperature Ranges</b>	400...1300 °C 500...1600 °C	400...1000 °C	50... 400 °C 75... 500 °C	400...2000 °C
<b>Spectral Range</b>	Narrow band in the near infrared	Narrow band in the near infrared	3.43 µm	CO <sub>2</sub> absorption band for hot CO <sub>2</sub> gases
<b>Measurement Uncertainty</b>	< 1500 °C: 0.3% oR + 1 °C > 1500 °C: 0.5% oR	< 1500 °C: 0.3% oR + 1 °C > 1500 °C: 0.5% oR	< 400 °C: 2.5 °C > 400 °C: 0.4% oR + 1 °C	<1300 °C: 0.6% oR >1300 °C: 0.8% oR
<b>Repeatability</b>	0.1% oR + 1 °C	0.1% oR + 1 °C	0.1% oR + 1 °C	0.1% oR + 1 °C
<b>Optics</b>	3 optical heads: Optics I: 3 fixed distances Optics II: 4 fixed distances Optics II: 6 focusable optics	3 optical heads: Optics I: 3 fixed distances Optics II: 4 fixed distances Optics II: 6 focusable optics	3 focusable optics: a = 100...142 mm a = 185...390 mm a = 305...1900 mm	3 focusable optics: a = 115...170 mm a = 210...500 mm a = 360...10000 mm
<b>Field of View</b> (Minimum spot size Ø in mm)	Optics I: 100:1 (1.2 mm) Optics II: min. 200:1 (0.45 mm)	Optics I: 35:1 (3.3 mm) Optics II: min. 85:1 (1.1 mm)	min. 50:1 (min. 2.1 mm)	min. 120:1 (min. 1.1)
<b>Alignment</b>	Laser targeting	Laser targeting	Laser targeting or through-lens-sighting	Laser targeting or through-lens-sighting
<b>Exposure time t<sub>90</sub></b>	< 1 ms, adjustable up to 10 s	< 1 ms, adjustable up to 10 s	1.5 ms, adjustable up to 10 s	1.5 ms, adjustable up to 10 s
<b>Output</b>	0/4...20 mA, RS232 or RS485 (switchable)	0/4...20 mA, RS232 or RS485 (switchable)	0/4...20 mA, RS232/ RS485 (switchable)	0/4...20 mA, RS232/ RS485 (switchable)

## UV 400 & UVR 400

Next generation of temperature sensors developed specifically for GaN-based MOCVD epitaxy processes (metal-organic chemical vapor deposition).

Improve yield through true wafer temperature measurement

Setting new standards for LED production processes (reliable correlation between process temperature and final product wavelength)

Measure temperature directly on the GaN layer using UV wavelength instrumentation

Real time measurement of deposition thickness using a high-speed reflectometer (UVR 400)



## M67S

## SERIES UV 400, 315



### M67S 7.9 μm

### M67S CO<sub>2</sub>

### UV 400, UVR 400

### PhotriX

### IGA 315-K

Analog 2-wire pyrometer with view finder. Special filter for thin plastic films or thin glass.

Analog 2-wire pyrometer with view finder. For measurement of combustion flames and hot gases containing CO<sub>2</sub>.

Digital pyrometers with extremely short wavelength (in the UV spectral range) for true Wafer Surface Temperature and Reflectance Instrumentation for GaN-based MOCVD epitaxy processes. The UVR 400 includes an additional reflectometer at 635 nm with 0.5 kHz measurement speed. This enables measurement of deposition thickness. These pyrometers are also suitable for measurements on uncoated silicon wafers.

Digital, extremely sensitive pyrometer to measure small signals and lower temperatures. Configurable collection optics: lens optic, lightpipe optics, fiber optics to remote lens, fiber optics to lightpipe.

Portable pyrometer for non-contact temperature measurement of nozzle bricks and air stages in coking ovens at standard distances between 1 and 12 m.

0...300 °C  
100...400 °C  
150...600 °C

320...1200 °C  
400...1400 °C  
450...1900 °C  
800...2200 °C

650...1300 °C

various ranges between  
30...2600 °C

600...1600 °C

7.9 μm

CO<sub>2</sub> hot band

383...410 nm

5 ranges: 0.65 μm, 0.88 μm,  
0.9 μm, 1.55 μm, 0.7...1.65 μm

1.58...1.8 μm

±0.5% of full scale or 1 °C

±0.5% of full scale or 1 °C

< 1000 °C: 3 °C  
> 1000 °C: 0.3% oR

±1.5 °C or 0.15% oR

0.75% oR

±0.2% of full scale span

±0.2% of full scale span

0.1% oR + 0.1 °C

0.1 °C

< 0.3% oR

1 focusable optics:  
350 mm...∞  
1 fixed optics  
a = 50 mm

2 focusable optics:  
350 mm...∞  
150...350 mm

fixed optics

Configurable collection optics:  
Fixed Optics, Lightpipe, or Fiber  
Optics with fixed optics or  
Lightpipe

Focusable optics:  
1000...12000 mm

Focusable optics:  
min. 30:1 (11.9 mm)  
Fixed: min. 30:1 (1.5 mm)

min. 30:1  
(1.8 mm)

min 8:1  
(9.8)

Optics or lightpipes adapted  
to customers request  
(min 0.5 mm)

~ 300:1 (e.g. 30 mm @ 9 m  
distance)

Through-lens-sighting

Through-lens-sighting

—

—

Through-lens-sighting

100 ms

300 ms

Integration Time:  
Min of 8 ms

1 ms, adjustable up to 60 s

10 ms

4...20 mA

4...20 mA

0/4...20 mA,  
RS485

4...20 mA, 0...10 V, RS232,  
RS485

USB Interface adapter